



Docket No.: A8319.0034/P034
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yoshiaki Nagashima et al.

Application No.: 10/780,751

Art Unit: 2856

Filed: February 19, 2004

Examiner: John E. Chapman, Jr.

For: NONDESTRUCTIVE INSPECTION
APPARATUS AND NONDESTRUCTIVE
INSPECTION METHOD USING ELASTIC
GUIDED WAVE

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

U.S. Patent and Trademark Office
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Randolph Building
401 Dulany Street
Alexandria, VA 22314

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, the Examiner's attention is directed to the additional references listed on the attached Form PTO/SB/08. It is respectfully requested that the information be expressly considered during the prosecution of the above-captioned application and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Supplemental Information Disclosure Statement is being filed together with a Request for Continued Examination (RCE) Transmittal.

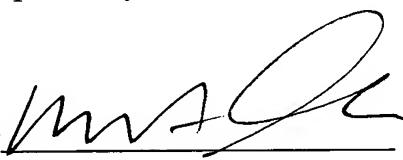
The listed documents were cited either in an Office Action that issued in a corresponding Japanese application or in a corresponding Korean application. It is to be noted that Japan 10-507530 corresponds to WO 9612951, which was cited in the Information Disclosure Statement filed on February 19, 2004. Copies of the foreign-language documents, including English-language abstracts, were provided to the Examiner with the Supplemental Information Disclosure Statement filed on April 13, 2006, together with copies of the Japanese and Korean Office Actions.

Japan 2003-57213 and JP 10-507530 relate to a non-destruction detective apparatus. Japan 10-185884 relates to the control of an output waveform.

This Supplemental Information Disclosure Statement should not constitute an admission that any patent, publication or other information referred to herein is "prior art" unless specifically designated as such. In accordance with 37 C.F.R. § 1.97(g), the filing of this Supplemental Information Disclosure Statement should not be construed to mean that a search has been made. This Supplemental Information Disclosure Statement is believed to be in compliance with 37 C.F.R. § 1.98 and the Examiner is respectfully requested to consider the listed references.

Dated: May 5, 2006

Respectfully submitted,

By 

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PTO/SB/08a/b (07-05)

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Substitute for form 1449A/B/PTO				Complete if Known	
				Application Number	10/780,751
				Filing Date	February 19, 2004
				First Named Inventor	Yoshiaki Nagashima
				Art Unit	2856
				Examiner Name	John E. Chapman, Jr.
Sheet	1	of	1	Attorney Docket Number	A8319.0034/P034

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
CA		2002/0062693 A1	05/2002	Gorman et al.	

FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)			
CB		JP 10-185884	07/1998		X*
CC		JP 10-507530	07/1998		X*
CD		JP 11-223622	08/1999		X*
CE		JP 2003-57213	02/2003		X*

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²

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*Abstract only.

Examiner Signature	Date Considered
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